Applicant(s)/Patent Under Application/Control No. Reexamination 10/628,923 MOITRA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 3661 Yonel Beaulieu **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY Α US-5,899,955 A 05-1999 Yagyu et al. 701/209 US-В С US-US-D US-Ε F US-G US-Н US-USı US-J K US-US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S

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U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)

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